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Application/Control No.	Applicant(s)/Patent under Reexamination		
09/855,015	CHANG ET AL.	CHANG ET AL.	
Examiner	Art Unit	Art Unit	
Bob A. Phunkulh	2616	2616	

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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See atta	achment	9/1/2006	ВАР

DATE	EXMR
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